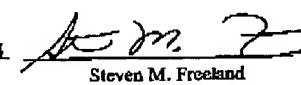


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SSB 2969.004  
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Appln. No.:	10/065,589	<b><u>Certificate of Transmission/Mailing</u></b>  I hereby certify that this correspondence is being facsimile transmitted to the USPTO, Fax. No. (703) 872-9306, or deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date shown below:  10/04/2004  Date Steven M. Freehand Registration No. 42,555 Attorney for Applicants
Applicants:	Paterson, et al.	
Filed:	October 31, 2002	
Title:	<b>METHOD OF PREPARING WHOLE SEMICONDUCTOR WAFER FOR ANALYSIS</b>	
Examiner:	GOUDREAU, George A.	
Art Unit:	1763	
Customer No.:	26375	
Confirm. No.:	9771	

**AMENDMENT A**

Mail Stop Amendment  
Hon. Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Responsive to the Office Action mailed June 3, 2004, Applicants provide the following:

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